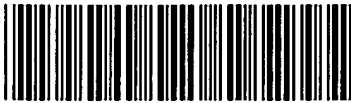


Search Notes



Application/Control No.

10/643,078

Examiner

David Q. Nguyen

Applicant(s)/Patent under Reexamination

NAKAZAWA ET AL.

Art Unit

2681

SEARCHED

Class	Subclass	Date	Examiner
455	423-425	05/24/06	DN
	63.1		
	63.2		
	67.11		
	67.13		
	67.2		
	560		
450	561	05/24/06	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East search	05/24/06	DN
Text search	05/24/06	DN